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LIST OF RELEVANT ART CITED BY APPLICANT (Use several sheets if necessary)	Applicants: Michael R. Rice, et al	
	Filing Date: January 26, 2004	Group: 2125

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CK	US-2	5,668,056	09/16/97	Wu et al.			
CK	US-3	5,976,199	11/02/99	Wu et al.			
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CK	OT-1	"300mm single-wafer transport", July 1999, Solid State Technology - semiconductor manufacturing and wafer fabrication, Semicon West '99 Product Spotlight, pg. 5.
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CK	OT-3	Griessing, Juergen et al., "Assessing the feasibility of a 300-mm test and monitor wafer handeling and logistics system", July 2000, Micro: The 300-mm Imperative, pgs. 1-19.

Examiner Charles Kim — Date Considered 12/9/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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U.S. Department of Commerce, Patent and Trademark Office	Docket No.: 8201/Y01/SYNX/JW	Serial No.: 10/764,620
LIST OF RELEVANT ART CITED BY APPLICANT (Use several sheets if necessary)	Applicants: Michael R. Rice, et al	
	Filing Date: January 26, 2004	Group: 2125

U.S. Patent Documents

*Examiner Initial		Document Number	Issue Date	Name	Class	Subclass	Filing Date If Appropriate
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	US-13						
	US-14						
	US-15						
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	US-17						
	US-18						
	US-19						
	US-20						
	US-21						
	US-22						

Foreign Patent Documents

		Document Number	Date	Country	Class	Subclass	Translation Yes	Translation No
	F-6							
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CR	OT-4	"The Leading Company in Micro environment", January 3, 2002, Incam Solutions Company, pgs. 1-2.
CR	OT-5	"Improved wafer isolation and additional flexibility", January 3, 2002, Incam Solutions Company SWIF technology, pgs. 1-2.
CR	OT-6	"SEMI standards compliance" and "Related SEMI standards", January 3, 2002, Incam Solutions Related standards, pg. 1.

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		Document Number	Date	Country	Class	Subclass	Translation Yes	Translation No
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CK	OT-7	"Single Wafer Lots Solution", January 3, 2002, Incam Solutions References, pg. 1.
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Examiner Chuck Kendall Date Considered 12/9/05

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		Document Number	Date	Country	Class	Subclass	Translation Yes	Translation No
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	F-4							
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Examiner: Charles Kasenge Date Considered 12/9/05

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	Filing Date: January 26, 2004	Group: 2125

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CK	US-5	4,775,046	10/04/88	Gramarossa et al.			
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	F-3							
	F-4							
	F-5							

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	OT-2	
	OT-3	

Examiner: Chuck Kay — Date Considered: 12/9/05

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